

Notice of References Cited	Application/Control No. 09/950,038	Applicant(s)/Patent Under Reexamination ZAIT ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6333485	12-2001	Haight et al.	219/121.68
	B	US-5463200	10-1995	James et al.	219/121.68
	C	US-4190759	02-1980	Hongo et al.	219/121M
	D	US-3889272	06-1975	Lou et al.	346/135
	E	US-4727234	02-1988	Oprysko et al.	219/121L
	F	US-6190836	02-2001	Grenon et al.	430/311
	G	US-6346352	02-2002	Hayden et al.	430/5
	H	US-5208818	05-1993	Gelbart et al.	372/30
	I	US-5830606	11-1998	Okamoto	430/5
	J	US-5395718	03-1995	Jensen et al.	430/5
	K	US-4923772	05-1990	Kirch et al.	430/5
	L	US-4529991	07-1985	Wada et al.	346/76L
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Ihleman et al. "Excimer laser ablation patterning of dielectric layers", Applied Surf. Sci., Vol. 86(1-4) pp. 228-233 (abstract only)
	V	Haight et al., "Implementation and performance of a femtosecond laser mask repair system in manufacturing", Proc. SPIE vol. 3546, pp. 477-484
	W	Shani et al., "high resolution near field mask repair with femtosecond laser
	X	O'Connor et al. "Next generation laser based mask repair tool", Proc. SPIE vol. 1604 pp. 167-178 (1991)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Haight et al., "MARS:Femtosecond laser mask advanced repair system in manufacturing", J Vac. Sci. Technol. B 17(6) pp 3137-3143 (Nov/Dec 1999)
	V	
	W	
	X	

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